## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10824434	YOON ET AL.
Examiner	Art Unit
Tan, Alvin H	2173

SEARCHED					
Class		Subclass	Date	Examiner	
715	744, 747		5/3/07 (Updated	/AT/ (/AT/)	

SEARCH NOTES		
Search Notes	Date	Examiner
715/745, 746 (text search only - see search history printout)	5/3/07 (Updated 6/19/10)	/AT/ (/AT/)
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/3/07 (Updated 6/19/10)	/AT/ (/AT/)
NPL - ACM Portal	5/4/07	AT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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